

Abstract

A semiconductor test system having a tester and a prober and the test method thereof are proposed. A test mark signal and a control board having a discrimination circuit and a protection circuit are added to a test connection 5 interface of the tester. When performing multi-chip test, the connection result is displayed after checking the test mark signal by the discrimination circuit. Whether the test can be performed or not is then determined by the protection circuit. When the interface connection is incorrect due to man-made carelessness, an alarm will buzz for warning, and the protection circuit will be 10 simultaneously activated to disable the tester. Normal test can be performed only if the interface connection is correct. Thereby, the correctness of the test results can be ensured to reduce returned purchase and to enhance the quality of production.